MIC Workshop: Serial Block Face Scanning Electron Microscopy

Date: 1 day; on demand
Trainers: Prof. Dr. phil. nat. Benoît Zuber
Number of participants: 2-4
KSL Stamm-Nr.: Will be entered on request
Reward: 0.5 ECTS
Description: The students will get an overview of sample preparation for serial block face scanning electron microscopy (SBF-SEM). They will get a demonstration of sample mounting in the microscope, three-dimensional data acquisition, and data visualization.
Assessment: To be determined